

<b>NOTICE OF REVISION (NOR)</b>		1. DATE (YYMMDD) 94-05-25	Form Approved OMB No. 0704-0188
THIS REVISION DESCRIBED BELOW HAS BEEN AUTHORIZED FOR THE DOCUMENT LISTED.			
<small>Public reporting burden for this collection is estimated to average 2 hours per response, including the time for reviewing instructions, searching existing data sources, gathering and maintaining the data needed, and completing and reviewing the collection of information. Send comments regarding this burden estimate or any other aspect of this collection of information, including suggestions for reducing this burden, to Department of Defense, Washington Headquarters Services, Directorate for Information Operations and Reports, 1215 Jefferson Davis Highway, Suite 1204, Arlington, VA 22202-4302, and to the Office of Management and Budget, Paperwork Reduction Project (0704-0188), Washington, DC 20503. PLEASE DO NOT RETURN YOUR COMPLETED FORM TO EITHER OF THESE ADDRESSES. RETURN COMPLETED FORM TO THE GOVERNMENT ISSUING CONTRACTING OFFICER FOR THE CONTRACT/ PROCURING ACTIVITY NUMBER LISTED IN ITEM 2 OF THIS FORM.</small>		2. PROCURING ACTIVITY NO.	
		3. DODAAC	
4. ORIGINATOR	b. ADDRESS ( <i>Street, City, State, Zip Code</i> ) Defense Electronics Supply Center 1507 Wilmington Pike Dayton, OH 45444-5270	5. CAGE CODE 67268	6. NOR NO. 5962-R194-94
a. TYPED NAME ( <i>First, Middle Initial, Last</i> )		7. CAGE CODE 67268	8. DOCUMENT NO. <b>5962-92117</b>
9. TITLE OF DOCUMENT MICROCIRCUIT, LINEAR, HIGH SPEED, LOW POWER, DUAL, OPERATIONAL AMPLIFIER, MONOLITHIC SILICON		10. REVISION LETTER	
		a. CURRENT A	b. NEW B
11. ECP NO. No users listed			
12. CONFIGURATION ITEM (OR SYSTEM) TO WHICH ECP APPLIES All			
13. DESCRIPTION OF REVISION			
<p>Sheet 1: Revisions ltr column; add "A". Revisions description column; add "Changes in accordance with NOR 5962-R194-94". Revisions date column; add "94-05-25". Revision level block; add "B". Rev status of sheets; for sheets 1, 7, and 8, add "B".</p> <p>Sheet 7: TABLE I. Slew rate test. Under the "Test" column, delete footnote "<u>7</u>" entirely. With the symbol of "SR-" and the condition of "<math>V_S = \pm 15 V</math>", delete the group A subgroup 4 value of "200 V/<math>\mu</math>s" and substitute "180 V/<math>\mu</math>s". Full power bandwidth test. Under the "Test" column, footnote "<u>8</u>" will be renumbered as footnote "<u>7</u>". Revision level block; delete "A" and substitute "B".</p> <p>Sheet 8: TABLE I. Delete footnote "<u>7</u>" entirely. Rise time test. Under the "Test" column, footnote "<u>9</u>" will be renumbered as footnote "<u>8</u>". Fall time test. Under the "Test" column, footnote "<u>9</u>" will be renumbered as footnote "<u>8</u>". Footnote "<u>8</u>" will be renumbered as footnote "<u>7</u>". Footnote "<u>9</u>" will be renumbered as footnote "<u>8</u>". Revision level block; delete "A" and substitute "B".</p>			
14. THIS SECTION FOR GOVERNMENT USE ONLY			
a. ( <i>X one</i> )	X	(1) Existing document supplemented by the NOR may be used in manufacture.	
		(2) Revised document must be received before manufacturer may incorporate this change.	
		(3) Custodian of master document shall make above revision and furnish revised document.	
b. ACTIVITY AUTHORIZED TO APPROVE CHANGE FOR GOVERNMENT DESC-ELDS		c. TYPED NAME ( <i>First, Middle Initial, Last</i> ) MICHAEL A. FRYE	
d. TITLE MICROELECTRONICS BRANCH CHIEF	e. SIGNATURE MICHAEL A. FRYE		f. DATE SIGNED (YYMMDD) 94-05-25
15a. ACTIVITY ACCOMPLISHING REVISION DESC-ELDS	b. REVISION COMPLETED ( <i>Signature</i> ) RICK C. OFFICER		c. DATE SIGNED (YYMMDD) 94-05-25

<b>NOTICE OF REVISION (NOR)</b> (See MIL-STD-480 for instructions)		<b>DATE (YYMMDD)</b> <b>93-04-06</b>	Form Approved OMB No. 0704-0188
This revision described below has been authorized for the document listed.			
Public reporting burden for this collection is estimated to average 1 hour per response, including the time for reviewing instructions, searching existing data sources, gathering and maintaining the data needed, and completing and reviewing the collection of information. Send comments regarding this burden estimate or any other aspect of this collection of information, including suggestions for reducing this burden, to Washington Headquarters Services, Directorate for Information Operations and Reports, 1215 Jefferson Davis Highway, Suite 1204, Arlington, VA 22202-4302, and to the Office of Information and Regulatory Affairs, Office of Management and Budget, Washington, DC 20503.			
<b>1. ORIGINATOR NAME AND ADDRESS</b>  Defense Electronics Supply Center Dayton, Ohio 45444-5277		<b>2. CAGE CODE</b>  67268	<b>3. NOR NO.</b>  5962-R077-93
		<b>4. CAGE CODE</b>  67268	<b>5. DOCUMENT NO.</b>  <b>5962-92117</b>
<b>6. TITLE OF DOCUMENT</b>  Mckts, Linear, High-speed, Low power, Dual, Operational Amplifier, Monolithic Silicon		<b>7. REVISION LETTER</b>  (Current) New	(New) A
		<b>8. ECP NO.</b> No registered users	
<b>9. CONFIGURATION ITEM (OR SYSTEM) TO WHICH ECP APPLIES</b>  All			
<b>10. DESCRIPTION OF REVISION</b>  Sheet 1: Revisions ltr column; add "A". Revisions description column; add "Changes in accordance with NOR 5962-R077-93". Revisions date column; add "93-04-06". Revision level block; add "A". Rev status above sheet number 1, 3, 5, 7, 8, and 11, add "A". Sheet 3: 1.3, Input common mode voltage range ( $V_{CM}$ ), delete " $V_S$ " and substitute " $\pm V_S$ ". Revision level block; add "A". Sheet 5: Table I, Quiescent power supply current test, $I_Q$ , conditions column, delete " $V_S = \pm 5.0$ V" and substitute " $V_S = \pm 5.0$ V, $V_{OUT} = 0$ V" and delete " $V_S = \pm 15.0$ V" and substitute " $V_S = \pm 15.0$ V, $V_{OUT} = 0$ V". Revision level block; add "A". Sheet 7: Table I, Settling time test, $t_S$ , delete subgroup "9" and substitute subgroup "4". Revision level block; add "A". Sheet 8: Table I, Overshoot test, OS, delete subgroup "9" and substitute subgroup "4". Rise time test, $t_R$ , delete subgroups "9, 10, and 11" and substitute subgroups "4, 5, 6". Fall time test, $t_F$ , delete subgroups "9, 10, and 11" and substitute subgroups "4, 5, 6". Delete footnote "1/" and substitute "1/ Unless otherwise specified, for dc tests, source resistance ( $R_S$ ) < 100 $\Omega$ , load resistance ( $R_L$ ) > 100 k $\Omega$ , and $V_{OUT} = 0$ V." Revision level block; add "A". Sheet 11: Table IIA, group A test requirements, delete subgroups "9, 10, and 11" (five times). Group B end-point electrical parameters, delete subgroups "9, 10, and 11" (two times). Revision level block; add "A".			
<b>11. THIS SECTION FOR GOVERNMENT USE ONLY</b>			
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b. ACTIVITY AUTHORIZED TO APPROVE CHANGE FOR GOVERNMENT  DESC-ECS	SIGNATURE AND TITLE  Michael A Frye  Branch Chief	DATE (YYMMDD)  93-04-06	
<b>12. ACTIVITY ACCOMPLISHING REVISION</b>  DESC-ECS	REVISION COMPLETED (Signature)  Marcia B Kelleher	DATE (YYMMDD)  93-04-06	

REVISIONS

LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED

REV																				
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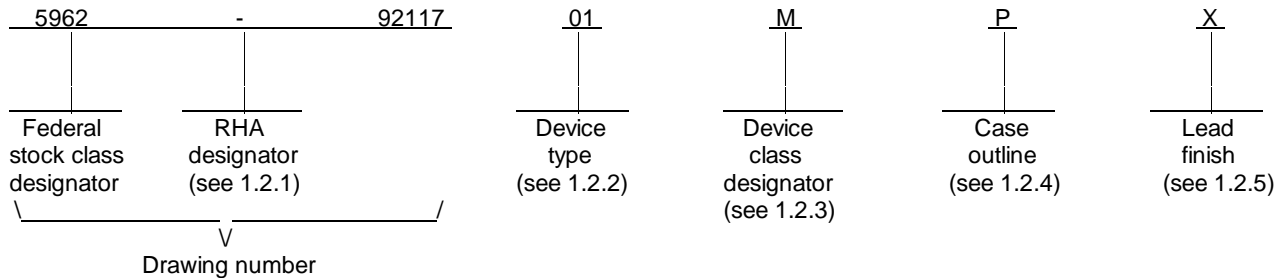
REV STATUS OF SHEETS	REV																			
	SHEET	1	2	3	4	5	6	7	8	9	10	11	12	13						

PMIC N/A	PREPARED BY Rick C. Officer	<b>DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444</b>																	
<b>STANDARDIZED MILITARY DRAWING</b>  THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE  AMSC N/A	CHECKED BY Charles E. Besore	MICROCIRCUIT, LINEAR, HIGH SPEED, LOW POWER, DUAL OPERATIONAL AMPLIFIER, MONOLITHIC SILICON																	
	APPROVED BY Michael A. Frye																		
	DRAWING APPROVAL DATE 92-06-16	SIZE <b>A</b>	CAGE CODE <b>67268</b>	<b>5962-92117</b>															
	REVISION LEVEL	SHEET 1 OF 13																	

1. SCOPE

1.1 Scope. This drawing forms a part of a one part - one part number documentation system (see 6.6 herein). Two product assurance classes consisting of military high reliability (device classes B, Q, and M) and space application (device classes S and V), and a choice of case outlines and lead finishes are available and are reflected in the Part or Identifying Number (PIN). Device class M microcircuits represent non-JAN class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices". When available, a choice of radiation hardness assurance (RHA) levels are reflected in the PIN.

1.2 PIN. The PIN shall be as shown in the following example:



1.2.1 Radiation hardness assurance (RHA) designator. Device classes M, B, and S RHA marked devices shall meet the MIL-M-38510 specified RHA levels and shall be marked with the appropriate RHA designator. Device classes Q and V RHA marked devices shall meet the MIL-I-38535 specified RHA levels and shall be marked with the appropriate RHA designator. A dash (-) indicates a non-RHA device.

1.2.2 Device type(s). The device type(s) shall identify the circuit function as follows:

<u>Device type</u>	<u>Generic number</u>	<u>Circuit function</u>
01	AD827	High speed, low power, dual operational amplifier

1.2.3 Device class designator. The device class designator shall be a single letter identifying the product assurance level as follows:

<u>Device class</u>	<u>Device requirements documentation</u>
M	Vendor self-certification to the requirements for non-JAN class B microcircuits in accordance with 1.2.1 of MIL-STD-883
B or S	Certification and qualification to MIL-M-38510
Q or V	Certification and qualification to MIL-I-38535

1.2.4 Case outline(s). The case outline(s) shall be as designated in MIL-STD-1835 and as follows:

<u>Outline letter</u>	<u>Descriptive designator</u>	<u>Terminals</u>	<u>Package style</u>
P	GDIP1-T8 or CDIP2-T8	8	Dual-in-line
2	CQCC1-N20	20	Square leadless chip carrier

1.2.5 Lead finish. The lead finish shall be as specified in MIL-M-38510 for classes M, B, and S or MIL-I-38535 for classes Q and V. Finish letter "X" shall not be marked on the microcircuit or its packaging. The "X" designation is for use in specifications when lead finishes A, B, and C are considered acceptable and interchangeable without preference.

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1.3 Absolute maximum ratings. 1/

Supply voltage ( $V_S$ )	.....	$\pm 18$ V dc
Input common mode voltage range ( $V_{CM}$ )	.....	$V_S$
Differential input voltage	.....	$\pm 6.0$ V dc
Storage temperature range	.....	$-65^\circ\text{C}$ to $+150^\circ\text{C}$
Internal power dissipation ( $P_D$ ):		
Case P	.....	1.3 W 2/
Case 2	.....	1.0 W 2/
Lead temperature (soldering, 60 seconds)	.....	$+300^\circ\text{C}$
Thermal resistance, junction-to-case ( $\theta_{JC}$ )	.....	See MIL-STD-1835
Thermal resistance, junction-to-ambient ( $\theta_{JA}$ )	.....	$110^\circ\text{C/W}$
Junction temperature ( $T_J$ )	.....	$+175^\circ\text{C}$

1.4 Recommended operating conditions.

Supply voltage range ( $V_S$ )	.....	$\pm 4.5$ V dc to $\pm 15$ V dc
Ambient operating temperature range ( $T_A$ )	.....	$-55^\circ\text{C}$ to $+125^\circ\text{C}$

2. APPLICABLE DOCUMENTS

2.1 Government specifications, standards, bulletin, and handbook. Unless otherwise specified, the following specifications, standards, bulletin, and handbook of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATIONS

MILITARY

- MIL-M-38510 - Microcircuits, General Specification for.
- MIL-I-38535 - Integrated Circuits, Manufacturing, General Specification for.

STANDARDS

MILITARY

- MIL-STD-480 - Configuration Control-Engineering Changes, Deviations and Waivers.
- MIL-STD-883 - Test Methods and Procedures for Microelectronics.
- MIL-STD-1835 - Microcircuit Case Outlines.

BULLETIN

MILITARY

- MIL-BUL-103 - List of Standardized Military Drawings (SMD's).

HANDBOOK

MILITARY

- MIL-HDBK-780 - Standardized Military Drawings.

(Copies of the specifications, standards, bulletin, and handbook required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

1/ Stresses above the absolute maximum rating may cause permanent damage to the device. Extended operation at the maximum levels may degrade performance and affect reliability.  
 2/ Maximum internal power dissipation is specified so that the junction temperature does not exceed  $+175^\circ\text{C}$ . For case P, derate at  $9\text{ mW}/^\circ\text{C}$  for  $T_A > +32^\circ\text{C}$  and for case 2, derate at  $6.6\text{ mW}/^\circ\text{C}$  for  $T_A > +25^\circ\text{C}$ .

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### 3. REQUIREMENTS

3.1 Item requirements. The individual item requirements for device class M shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein. The individual item requirements for device classes B and S shall be in accordance with MIL-M-38510 and as specified herein. For device classes B and S, a full electrical characterization table for each device type shall be included in this SMD. The individual item requirements for device classes Q and V shall be in accordance with MIL-I-38535, the device manufacturer's Quality Management (QM) plan, and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 for device classes M, B, and S and MIL-I-38535 for device classes Q and V and herein.

3.2.1 Case outline(s). The case outline(s) shall be in accordance with 1.2.4 herein.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 1.

3.3 Electrical performance characteristics and postirradiation parameter limits. Unless otherwise specified herein, the electrical performance characteristics and postirradiation parameter limits are as specified in table I and shall apply over the full ambient operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table IIA. The electrical tests for each subgroup are defined in table I.

3.5 Marking. The part shall be marked with the PIN listed in 1.2 herein. Marking for device class M shall be in accordance with MIL-STD-883 (see 3.1 herein). In addition, the manufacturer's PIN may also be marked as listed in MIL-BUL-103. Marking for device classes B and S shall be in accordance with MIL-M-38510. Marking for device classes Q and V shall be in accordance with MIL-I-38535.

3.5.1 Certification/compliance mark. The compliance mark for device class M shall be a "C" as required in MIL-STD-883 (see 3.1 herein). The certification mark for device classes B and S shall be a "J" or "JAN" as required in MIL-M-38510. The certification mark for device classes Q and V shall be a "QML" as required in MIL-I-38535.

3.6 Certificate of compliance. For device class M, a certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-BUL-103 (see 6.7.3 herein). For device classes Q and V, a certificate of compliance shall be required from a QML-38535 listed manufacturer in order to supply to the requirements of this drawing (see 6.7.2 herein). The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply for this drawing shall affirm that the manufacturer's product meets, for device class M the requirements of MIL-STD-883 (see 3.1 herein), or for device classes Q and V, the requirements of MIL-I-38535 and the requirements herein.

3.7 Certificate of conformance. A certificate of conformance as required for device class M in MIL-STD-883 (see 3.1 herein) or device classes B and S in MIL-M-38510 or for device classes Q and V in MIL-I-38535 shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change for device class M. For device class M, notification to DESC-ECS of change of product (see 6.2 herein) involving devices acquired to this drawing is required for any change as defined in MIL-STD-480.

3.9 Verification and review for device class M. For device class M, DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

3.10 Microcircuit group assignment for device classes M, B, and S. Device classes M, B, and S devices covered by this drawing shall be in microcircuit group number 49 (see MIL-M-38510, appendix E).

3.11 Serialization for device class S. All device class S devices shall be serialized in accordance with MIL-M-38510.

### 4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. For device class M, sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein). For device classes B and S, sampling and inspection procedures shall be in accordance with MIL-M-38510 and method 5005 of MIL-STD-883, except as modified herein. For device classes Q and V, sampling and inspection procedures shall be in accordance with MIL-I-38535 and the device manufacturer's QM plan.

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions <u>1/</u> -55° C ≤ T <sub>A</sub> ≤ +125° C unless otherwise specified	Group A subgroups	Limits <u>2/</u>		Unit
				Min	Max	
Input offset voltage	V <sub>OS</sub>	V <sub>S</sub> = ±5.0 V, V <sub>CM</sub> = 0 V	1		±2.0	mV
			2, 3		±4.0	
		V <sub>S</sub> = ±15 V, V <sub>CM</sub> = 0 V	1		±2.0	
			2, 3		±5.0	
Input bias current	I <sub>IB</sub>	V <sub>S</sub> = ±5.0 V and ±15.0 V, V <sub>CM</sub> = 0 V	1		7.0	μA
			2, 3		9.5	
Input offset current	I <sub>OS</sub>	V <sub>S</sub> = ±5.0 V and ±15.0 V, V <sub>CM</sub> = 0 V	1		0.3	μA
			2, 3		0.4	
Output current <u>3/</u>	I <sub>OUT</sub>	V <sub>S</sub> = ±5.0 V, V <sub>OUT</sub> = ±2.5 V, T <sub>A</sub> = +25° C	4	16		mA
		V <sub>S</sub> = ±15 V, V <sub>OUT</sub> = ±10 V, T <sub>A</sub> = +25° C		20		
Common mode input voltage range <u>4/</u>	V <sub>CM</sub>	V <sub>S</sub> = ±5.0 V	1, 2, 3	±2.5		V
		V <sub>S</sub> = ±15 V		±12		
Quiescent power supply current	I <sub>Q</sub>	V <sub>S</sub> = ±5.0 V	1		13	mA
			2, 3		17.5	
		V <sub>S</sub> = ±15 V	1		13.5	
			2, 3		18	

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions <u>1/</u> -55° C ≤ T <sub>A</sub> ≤ +125° C unless otherwise specified	Group A subgroups	Limits <u>2/</u>		Unit
				Min	Max	
Quiescent power <u>5/</u> consumption	P <sub>Q</sub>	V <sub>S</sub> = ±5.0 V, V <sub>OUT</sub> = 0 V, I <sub>OUT</sub> = 0 mA	1		130	mW
			2, 3		175	
		V <sub>S</sub> = ±15 V, V <sub>OUT</sub> = 0 V, I <sub>OUT</sub> = 0 mA	1		405	
			2, 3		540	
Power supply rejection ratio	PSRR	V <sub>S</sub> = ±5.0 V to ±15 V	1	75		dB
			2, 3	72		
Open loop gain	A <sub>OL</sub>	V <sub>S</sub> = ±5.0 V, R <sub>L</sub> = 500Ω, V <sub>OUT</sub> = ±2.5 V	1	2.0		V/mV
			2, 3	1.0		
		V <sub>S</sub> = ±15 V, R <sub>L</sub> = 1.0 kΩ, V <sub>OUT</sub> = ±10 V	1	3.0		
			2, 3	1.5		
Common mode rejection ratio	CMRR	V <sub>S</sub> = ±5.0 V, V <sub>CM</sub> = ±2.5 V	1	80		dB
			2, 3	75		
		V <sub>S</sub> = ±15 V, V <sub>CM</sub> = ±12 V	1	80		
			2, 3	75		
Output voltage swing	V <sub>OUT</sub>	V <sub>S</sub> = ±5.0 V, R <sub>L</sub> = 500Ω	1	±3.0		V
			2, 3	±2.5		
		V <sub>S</sub> = ±5.0 V, R <sub>L</sub> = 150Ω	1	±2.5		
		V <sub>S</sub> = ±15 V, R <sub>L</sub> = 1 kΩ	1, 2, 3	±12		
		V <sub>S</sub> = ±15 V, R <sub>L</sub> = 500Ω	1	±10		

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions <u>1/</u> -55°C ≤ T <sub>A</sub> ≤ +125°C unless otherwise specified	Group A subgroups	Limits <u>2/</u>		Unit
				Min	Max	
Slew rate <u>3/ 6/ 7/</u>	SR+	V <sub>S</sub> = ±5.0 V, R <sub>L</sub> = 500Ω, A <sub>V</sub> = +1.0, V <sub>OUT</sub> = -2 V to +2 V, rising edge, measured at 10 percent to 90 percent	4	120		V/μs
			5, 6	90		
	SR-	V <sub>S</sub> = ±5.0 V, R <sub>L</sub> = 500Ω, A <sub>V</sub> = +1.0, V <sub>OUT</sub> = +2 V to -2 V, falling edge, measured at 10 percent to 90 percent	4	90		
			5, 6	65		
	SR+	V <sub>S</sub> = ±15 V, R <sub>L</sub> = 1 kΩ, A <sub>V</sub> = +1.0, V <sub>OUT</sub> = -5 V to +5 V, rising edge, measured at 10 percent to 90 percent	4	200		
			5, 6	90		
	SR-	V <sub>S</sub> = ±15 V, R <sub>L</sub> = 1 kΩ, A <sub>V</sub> = +1.0, V <sub>OUT</sub> = +5 V to -5 V, falling edge, measured at 10 percent to 90 percent	4	200		
			5, 6	137		
Differential input <u>3/</u> impedance	R <sub>IN</sub>	V <sub>CM</sub> = 0 V, T <sub>A</sub> = +25°C, V <sub>S</sub> = ±15 V	4	60		kΩ
Unity gain bandwidth <u>3/</u>	GBWP	V <sub>S</sub> = ±5.0 V, V <sub>OUT</sub> = ±100 mV, R <sub>L</sub> = 500Ω, T <sub>A</sub> = +25°C, A <sub>V</sub> = 1	4	25		MHz
		V <sub>S</sub> = ±15 V, V <sub>OUT</sub> = ±100 mV, R <sub>L</sub> = 1 kΩ, T <sub>A</sub> = +25°C, A <sub>V</sub> = 1		40		
Full power bandwidth <u>3/ 8/</u>	FPWP	V <sub>S</sub> = ±5.0 V, V <sub>PK</sub> = 2.5 V, R <sub>L</sub> = 500Ω, T <sub>A</sub> = +25°C	4	5.7		MHz
		V <sub>S</sub> = ±15 V, V <sub>PK</sub> = 10 V, R <sub>L</sub> = 1 kΩ, T <sub>A</sub> = +25°C		3		
Close loop stable gain <u>3/</u>	CLSG	V <sub>S</sub> = ±5.0 V, ±15 V, R <sub>L</sub> = 1.0 kΩ	4, 5, 6	1		V/V
Settling time <u>3/</u>	t <sub>s</sub>	V <sub>S</sub> = ±15 V, R <sub>L</sub> = 1.0 kΩ, A <sub>V</sub> = -1, 10 V step at 0.1 percent of the fixed value, T <sub>A</sub> = +25°C	9		150	ns

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions <sup>1/</sup> -55° C ≤ T <sub>A</sub> ≤ +125° C unless otherwise specified	Group A subgroups	Limits <sup>2/</sup>		Unit
				Min	Max	
Overshoot <sup>3/</sup>	OS	V <sub>S</sub> = ±15 V, R <sub>L</sub> = 1.0 kΩ, A <sub>V</sub> = 1, V <sub>OUT</sub> = 0 V to ±200 mV, T <sub>A</sub> = +25° C	9		30	%
Rise time <sup>3/ 9/</sup>	t <sub>R</sub>	V <sub>S</sub> = ±5.0 V, ±15 V, R <sub>L</sub> = 1.0 kΩ, V <sub>OUT</sub> = 0 V to +200 mV, A <sub>V</sub> = 1	9, 10, 11		10	ns
Fall time <sup>3/ 9/</sup>	t <sub>F</sub>	V <sub>S</sub> = ±5.0 V, ±15 V, R <sub>L</sub> = 1.0 kΩ, V <sub>OUT</sub> = 0 V to -200 mV, A <sub>V</sub> = 1	9, 10, 11		10	ns

- <sup>1/</sup> Unless otherwise specified, for dc tests, source resistance (R<sub>S</sub>) = 100Ω, load resistance (R<sub>L</sub>) = 100 kΩ, and V<sub>OUT</sub> = 0 V.  
<sup>2/</sup> The limiting terms "min" (minimum) and "max" (maximum) shall be considered to apply to magnitudes only. Negative current shall be defined as conventional current flow out of a device terminal.  
<sup>3/</sup> If not tested, shall be guaranteed to the limits specified in table I herein.  
<sup>4/</sup> This test is guaranteed by testing CMRR.  
<sup>5/</sup> Quiescent power consumption is based on quiescent supply current test maximum (no load outputs).  
<sup>6/</sup> Slew rate test limits are guaranteed after 5 minutes of warmup.  
<sup>7/</sup> Each date code shall be tested to and pass an LTPD of 15 with C = 0.  
<sup>8/</sup> Full power bandwidth = SR/(2π V<sub>PK</sub>).  
<sup>9/</sup> Rise and fall times are measured between 10 percent and 90 percent points.

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DEFENSE ELECTRONICS SUPPLY CENTER  
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Device type	01	
Case outlines	P	2
Terminal number	Terminal symbol	
1	OUTPUT 1	NC
2	INPUT- 1	OUTPUT 1
3	INPUT+ 1	NC
4	V <sub>S-</sub>	NC
5	INPUT+ 2	INPUT- 1
6	INPUT- 2	NC
7	OUTPUT 2	INPUT+ 1
8	V <sub>S+</sub>	NC
9	---	NC
10	---	V <sub>S-</sub>
11	---	NC
12	---	INPUT+ 2
13	---	NC
14	---	NC
15	---	INPUT- 2
16	---	NC
17	---	OUTPUT 2
18	---	NC
19	---	NC
20	---	V <sub>S+</sub>

FIGURE 1. Terminal connections.

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4.2 Screening. For device class M, screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. For device classes B and S, screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to qualification and quality conformance inspection. For device classes Q and V, screening shall be in accordance with MIL-I-38535, and shall be conducted on all devices prior to qualification and technology conformance inspection.

4.2.1 Additional criteria for device classes M, B, and S.

- a. Burn-in test, method 1015 of MIL-STD-883.
  - (1) Test condition B. For device class M, the test circuit shall be submitted to DESC-ECS for review with the certificate of compliance. For device classes B and S, the test circuit shall be submitted to the qualifying activity.
  - (2)  $T_A = +125^\circ\text{C}$ , minimum.
- b. Interim and final electrical test parameters shall be as specified in table IIA herein.

4.2.2 Additional criteria for device classes Q and V.

- a. The burn-in test duration, test condition and test temperature or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-I-38535. The burn-in test circuit shall be submitted to DESC-ECS with the certificate of compliance and shall be under the control of the device manufacturer's Technology Review Board (TRB) in accordance with MIL-I-38535.
- b. Interim and final electrical test parameters shall be as specified in table IIA herein.
- c. Additional screening for device class V beyond the requirements of device class Q shall be as specified in appendix B of MIL-I-38535 and as detailed in table IIB herein.

4.3 Qualification inspection.

4.3.1 Qualification inspection for device classes B and S. Qualification inspection for device classes B and S shall be in accordance with MIL-M-38510. Inspections to be performed shall be those specified in method 5005 of MIL-STD-883 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.5).

4.3.2 Qualification inspection for device classes Q and V. Qualification inspection for device classes Q and V shall be in accordance with MIL-I-38535. Inspections to be performed shall be those specified in MIL-I-38535 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.5).

4.4 Conformance inspection. Quality conformance inspection for device class M shall be in accordance with MIL-STD-883 (see 3.1 herein) and as specified herein. Quality conformance inspection for device classes B and S shall be in accordance with MIL-M-38510 and as specified herein. Inspections to be performed for device classes M, B, and S shall be those specified in method 5005 of MIL-STD-883 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.5). Technology conformance inspection for classes Q and V shall be in accordance with MIL-I-38535 including groups A, B, C, D, and E inspections and as specified herein except where option 2 of MIL-I-38535 permits alternate in-line control testing.

4.4.1 Group A inspection.

- a. Tests shall be as specified in table IIA herein.
- b. Subgroups 7 and 8 in table I, method 5005 of MIL-STD-883 shall be omitted.

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TABLE IIA. Electrical test requirements.

Test requirements	Subgroups (per method 5005, table I)			Subgroups (per MIL-I-38535, table III)	
	Device class M	Device class B	Device class S	Device class Q	Device class V
Interim electrical parameters (see 4.2)	1	1	1	1	1
Final electrical parameters (see 4.2)	1, 2, <u>1/</u> 3, 4, 5, 6	1, 2, <u>1/</u> 3, 4, 5, 6	1, 2, <u>1/</u> 3, 4, 5, 6	1, 2, <u>1/</u> 3, 4, 5, 6	1, 2, <u>1/</u> 3, 4, 5, 6
Group A test requirements (see 4.4)	1, 2, 3, 4, 5, 6, 9, 10, 11	1, 2, 3, 4, 5, 6, 9, 10, 11	1, 2, 3, 4, 5, 6, 9, 10, 11	1, 2, 3, 4, 5, 6, 9, 10, 11	1, 2, 3, 4, 5, 6, 9, 10, 11
Group B end-point electrical parameters (see 4.4)	---	---	1, 2, 3, 4, 5, 6, 9, 10, 11	---	1, 2, 3, 4, 5, 6, 9, 10, 11
Group C end-point electrical parameters (see 4.4)	1	1	---	1	---
Group D end-point electrical parameters (see 4.4)	1	1	1	1	1
Group E end-point electrical parameters (see 4.4)	---	---	---	---	---

1/ PDA applies to subgroup 1.

4.4.2 Group B inspection. The group B inspection end-point electrical parameters shall be as specified in table IIA herein.

4.4.3 Group C inspection. The group C inspection end-point electrical parameters shall be as specified in table IIA herein.

4.4.3.1 Additional criteria for device classes M, B, and S. Steady-state life test conditions, method 1005 of MIL-STD-883:

- a. Test condition B. For device class M, the test circuit shall be submitted to DESC-ECS for review with the certificate of compliance. For device classes B and S, the test circuit shall be submitted to the qualifying activity.
- b.  $T_A = +125^\circ\text{C}$ , minimum.
- c. Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

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TABLE IIB. Additional screening for device class V.

Test	MIL-STD-883, test method	Lot requirement
Particle impact noise detection	2020	100 percent
Internal visual	2010, condition A or approved alternate	100 percent
Nondestructive bond pull	2023 or approved alternate	100 percent
Reverse bias burn-in	1015	100 percent
Burn-in	1015, total of 240 hours at +125° C	100 percent
Radiographic	2012	100 percent

4.4.3.2 Additional criteria for device classes Q and V. The steady-state life test duration, test condition and test temperature or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-I-38535. The steady-state life test circuit shall be submitted to DESC-ECS with the certificate of compliance and shall be under the control of the device manufacturer's TRB in accordance with MIL-I-38535.

4.4.4 Group D inspection. The group D inspection end-point electrical parameters shall be as specified in table IIA herein.

4.4.5 Group E inspection. Group E inspection is required only for parts intended to be marked as radiation hardness assured (see 3.5 herein). RHA levels for device classes B, S, Q, and V shall be M, D, R, and H and for device class M shall be M and D. RHA quality conformance inspection sample tests shall be performed at the RHA level specified in the acquisition document.

- a. RHA tests for device classes B and S for levels M, D, R, and H or for device class M for levels M and D shall be performed through each level to determine at what levels the devices meet the RHA requirements. These RHA tests shall be performed for initial qualification and after design or process changes which may affect the RHA performance of the device.
- b. End-point electrical parameters shall be as specified in table IIA herein.
- c. Prior to total dose irradiation, each selected sample shall be assembled in its qualified package. It shall pass the specified group A electrical parameters in table I for subgroups specified in table IIA herein.
- d. For device classes M, B, and S, the devices shall be subjected to radiation hardness assured tests as specified in MIL-M-38510 for RHA level being tested, and meet the postirradiation end-point electrical parameter limits as defined in table I at  $T_A = +25^\circ\text{C} \pm 5$  percent, after exposure.
- e. Prior to and during total dose irradiation testing, the devices shall be biased to establish a worst case condition as specified in the radiation exposure circuit.
- f. For device classes M, B, and S, subgroups 1 and 2 in table V, method 5005 of MIL-STD-883 shall be tested as appropriate for device construction.
- g. When specified in the purchase order or contract, a copy of the RHA delta limits shall be supplied.

## 5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510 for device classes M, B, and S and MIL-I-38535 for device classes Q and V.

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6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.1.1 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.1.2 Substitutability. Device classes B and Q devices will replace device class M devices.

6.2 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-481 using DD Form 1693, Engineering Change Proposal (Short Form).

6.3 Record of users. Military and industrial users shall inform Defense Electronics Supply Center when a system application requires configuration control and which SMD's are applicable to that system. DESC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronic devices (FSC 5962) should contact DESC-ECS, telephone (513) 296-6021.

6.4 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone (513) 296-5377.

6.5 Abbreviations, symbols and definitions. The abbreviations, symbols, and definitions used herein are defined in MIL-M-38510 and MIL-STD-1331.

6.6 One part - one part number system. The one part - one part number system described below has been developed to allow for transitions between identical generic devices covered by the four major microcircuit requirements documents (MIL-M-38510, MIL-H-38534, MIL-I-38535, and 1.2.1 of MIL-STD-883) without the necessity for the generation of unique PIN's. The four military requirements documents represent different class levels, and previously when a device manufacturer upgraded military product from one class level to another, the benefits of the upgraded product were unavailable to the Original Equipment Manufacturer (OEM), that was contractually locked into the original unique PIN. By establishing a one part number system covering all four documents, the OEM can acquire to the highest class level available for a given generic device to meet system needs without modifying the original contract parts selection criteria.

<u>Military documentation format</u>	<u>Example PIN under new system</u>	<u>Manufacturing source listing</u>	<u>Document listing</u>
New MIL-M-38510 Military Detail Specifications (in the SMD format)	5962-XXXXXZZ(B or S)YY	QPL-38510 (Part 1 or 2)	MIL-BUL-103
New MIL-H-38534 Standardized Military Drawings	5962-XXXXXZZ(H or K)YY	QML-38534	MIL-BUL-103
New MIL-I-38535 Standardized Military Drawings	5962-XXXXXZZ(Q or V)YY	QML-38535	MIL-BUL-103
New 1.2.1 of MIL-STD-883 Standardized Military Drawings	5962-XXXXXZZ(M)YY	MIL-BUL-103	MIL-BUL-103

6.7 Sources of supply.

6.7.1 Sources of supply for device classes B and S. Sources of supply for device classes B and S are listed in QPL-38510.

6.7.2 Sources of supply for device classes Q and V. Sources of supply for device classes Q and V are listed in QML-38535. The vendors listed in QML-38535 have submitted a certificate of compliance (see 3.6 herein) to DESC-ECS and have agreed to this drawing.

6.7.3 Approved sources of supply for device class M. Approved sources of supply for class M are listed in MIL-BUL-103. The vendors listed in MIL-BUL-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DESC-ECS.

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STANDARDIZED MILITARY DRAWING SOURCE APPROVAL BULLETIN

DATE: 92-06-16

Approved sources of supply for SMD 5962-92117 are listed below for immediate acquisition only and shall be added to MIL-BUL-103 during the next revision. MIL-BUL-103 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DESC-ECS. This bulletin is superseded by the next dated revision of MIL-BUL-103.

Standardized Military drawing PIN	Vendor CAGE number	Vendor similar PIN <sup>1/</sup>
5962-9211701MPX	24355	AD827SQ/883B
5962-9211701M2X	24355	AD827SE/883B

<sup>1/</sup> Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number

24355

Vendor name and address

Analog Devices  
 Route 1 Industrial Park  
 P.O. Box 9106  
 Norwood, MA 02062  
 Point of contact: 804 Woburn Street  
 Wilmington, MA 01887

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